

Docket No. JCLA11354
US App. No. 10/655,850

IN THE SPECIFICATION:

Please amend paragraph [0009] on page 3 as follows:

[0009] Unfortunately, practitioners in the semiconductor industry still hazily utilize the kill ratio concept. To obtain useful yield impact information, it is desirable to establish a succinct "kill ratio" definition in order to filter out excursions in a control table, and show an effective expression for yield loss contribution for specific defect type.